

Conductor Modelling

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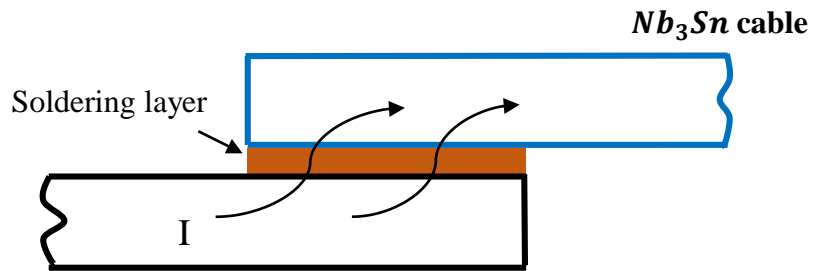
Update 18/09

Model

Framework: Cable + Connection joints.

Joint: a splice between a $NbTi$ and a Nb_3Sn cable (magnet leads), with soldering material as physical connection.

Real system

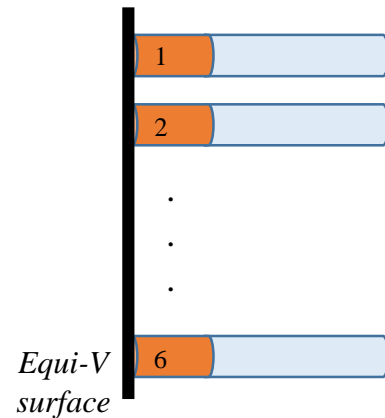


$NbTi$ cable

Model

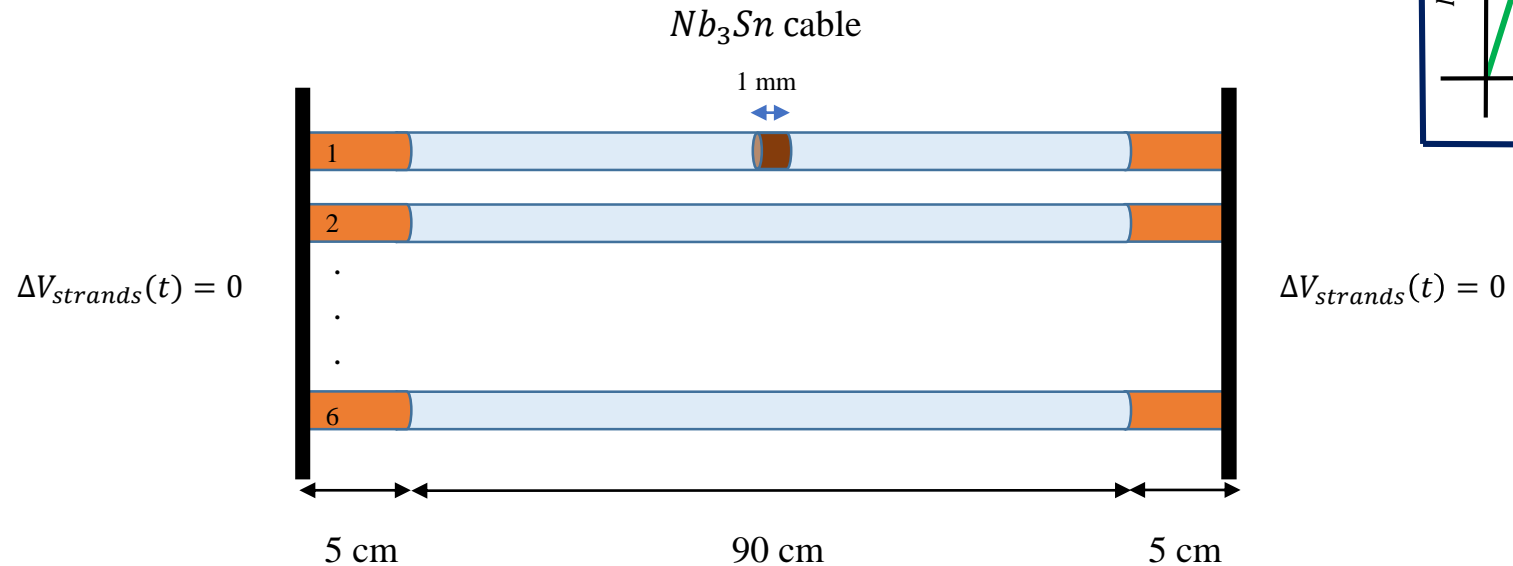
B.C.

Joint



Purely resistive part
 $J_c, T_c, T_{cs} = 0$

Model & Assumptions

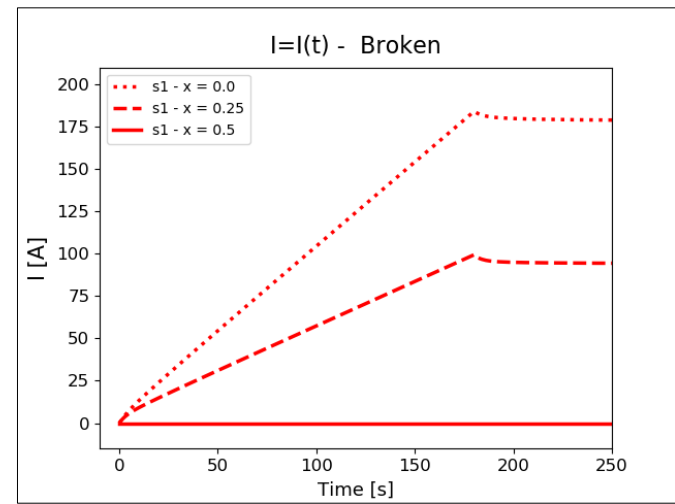
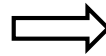
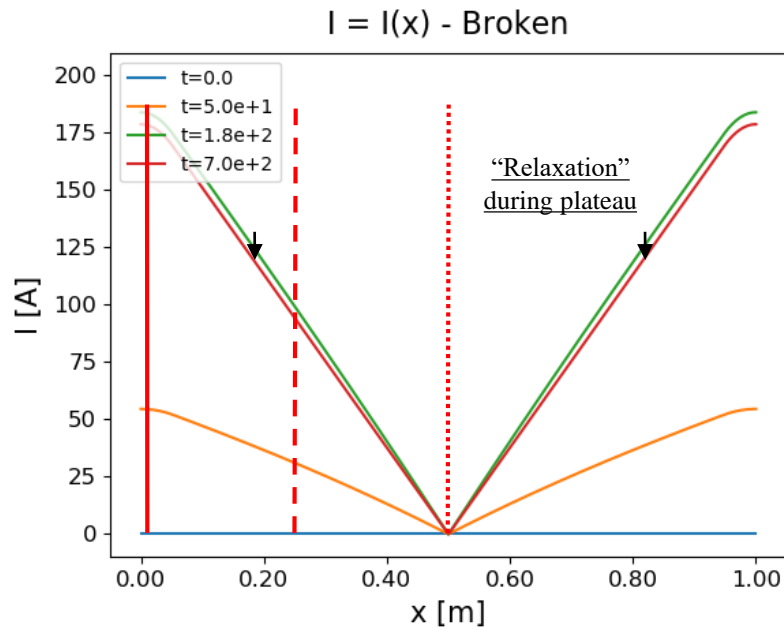


Assumptions

- Zero-voltage difference among strands in the $NbTi$ cable *before the joint* (equi-V condition).
- Current is forced to be transferred from $NbTi$ to Nb_3Sn strands through the Cu barrier of the strands themselves and the *soldering layer*. We define a *purely resistive, 5-cm region*, where superconducting properties (J_c, T_c, T_{cs}) are set to zero, and such that $R_{joint} = 1 \text{ n}\Omega$.

Results

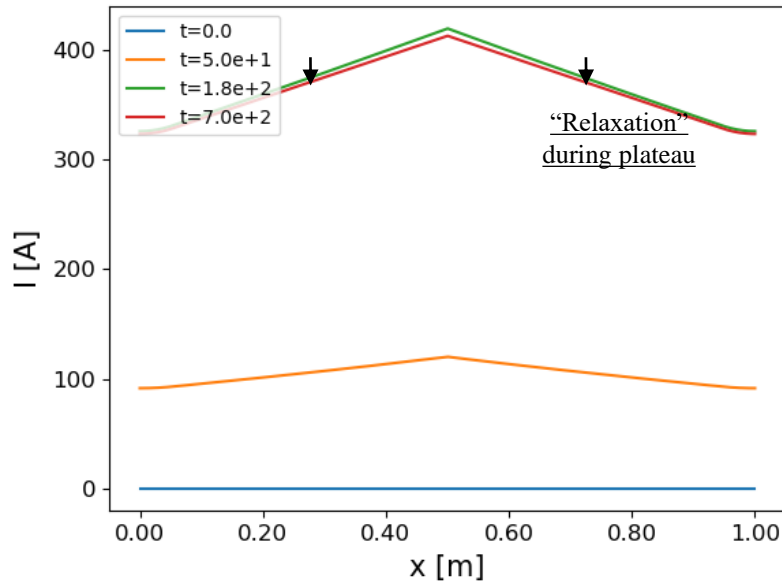
As reference, we start with: $R_{joint} = 1 \text{ n}\Omega \Leftrightarrow R_{joint,40 \text{ strands}} \approx 7 \text{ n}\Omega$



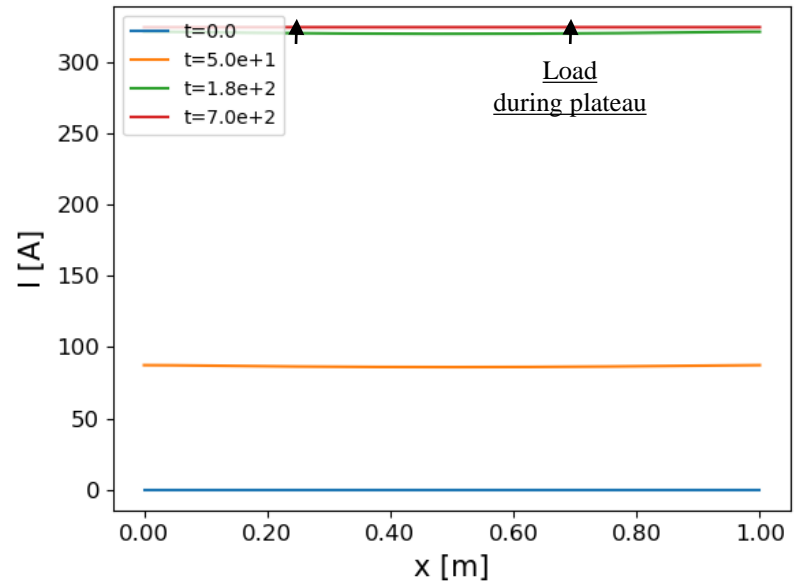
- V-shape profile evolution with boundary value $\sim 180 \text{ A}$ (intermediate)
- Relaxation during plateau

Results

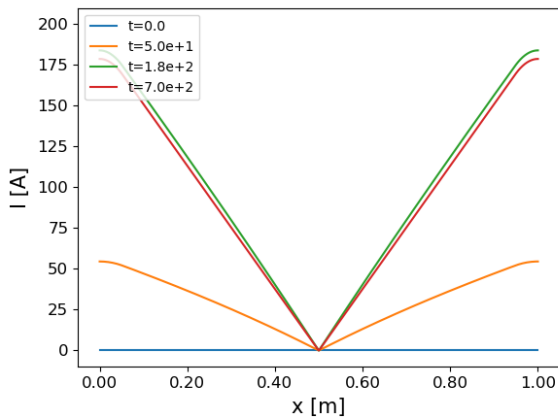
$I = I(x)$ - Adjacent



$I = I(x)$ - Crossing

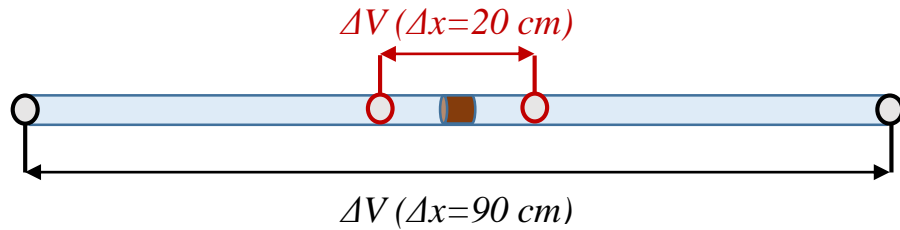


$I = I(x)$ - Broken



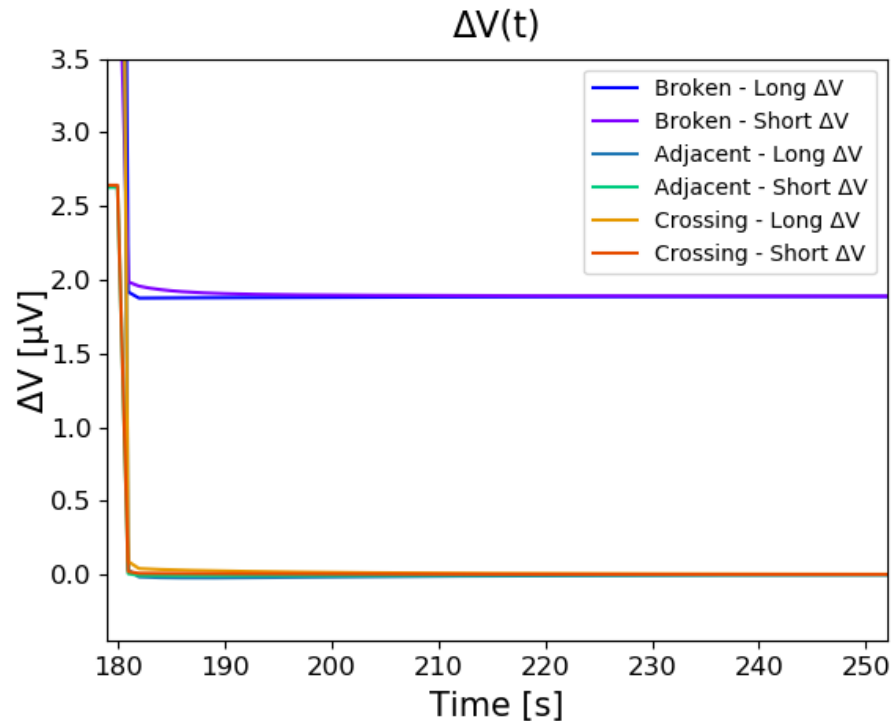
- Adjacent strands: current in sI has a smoother profile with respect to the case of imposed equal current distribution at the boundaries (see past presentations).
- Crossing strands: profile goes above 300 A, a sign that they contribute to the current distribution

Results



$\Delta V \rightarrow$ “Long”

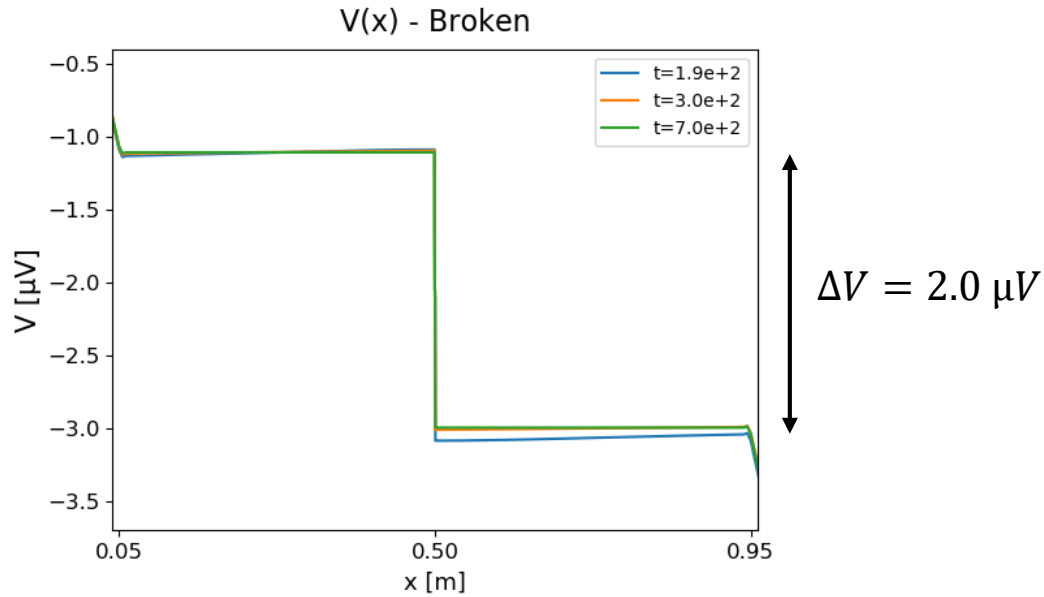
$\Delta V \rightarrow$ “Short”



- Broken strand remains the only to experience a relevant ΔV (*few μV*) along its length
- Adjacent strands are still the only to see $\Delta V < 0$, due to relaxation (current reduction) during plateau
- Crossing strands have $\Delta V > 0$, more relevant than with 40 strands (here we have only 3 crossing strands)

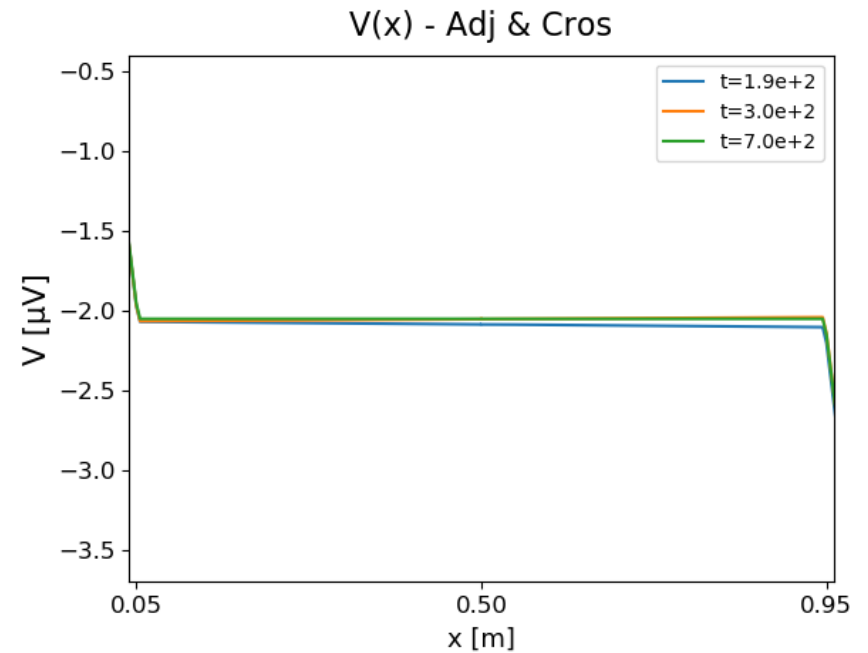
Results

An insight: voltage profile in space



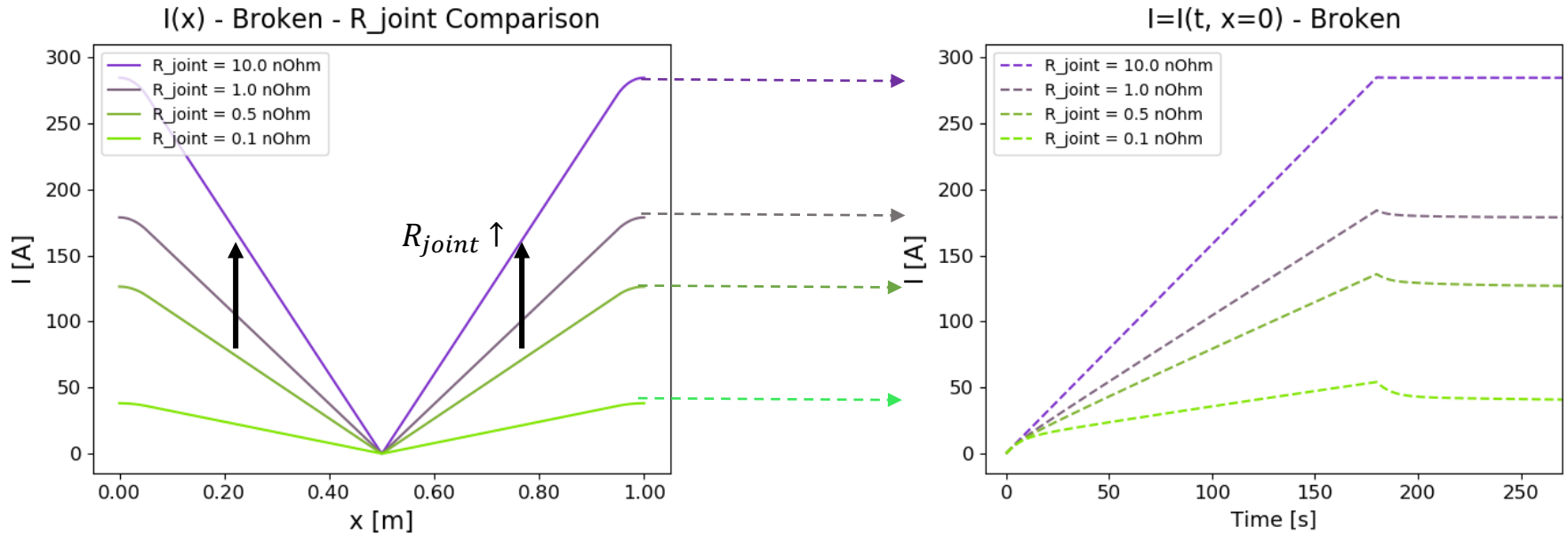
- *V variation is a step-like function*
→ no much different signals from farther and closer V taps.

- (Almost) flat profile in adjacent and crossing strands; still, evolution during plateau takes place



Parametric studies – Joint Resistance

We propose here a comparison for Currents $R_{joint} = 0.1, 0.5, 1.0, 10.0 \text{ n}\Omega$

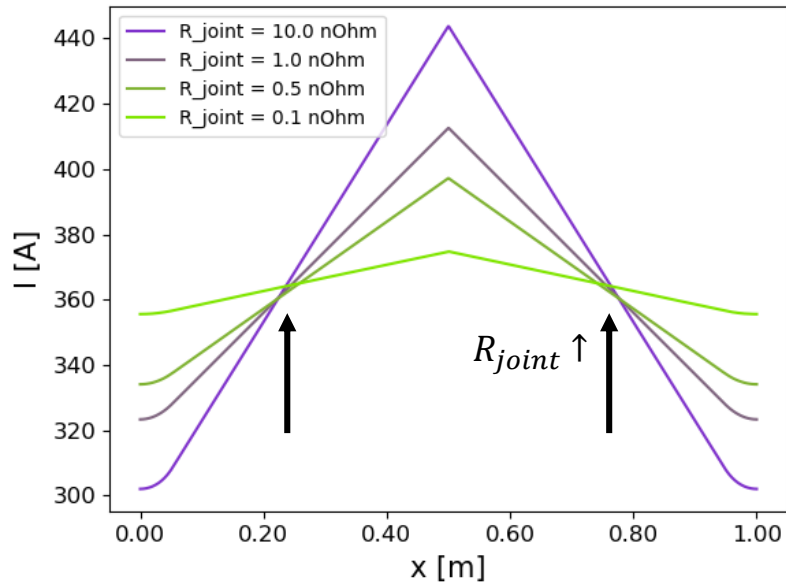


- As $R_{joint} \uparrow$, current at the boundaries gets closer to an equal distribution $\rightarrow I(x)$ profile gets steeper
- As $R_{joint} \uparrow$, the time constant of the system decreases ($\tau \approx L/R$) \rightarrow Evolution at ramp end is faster

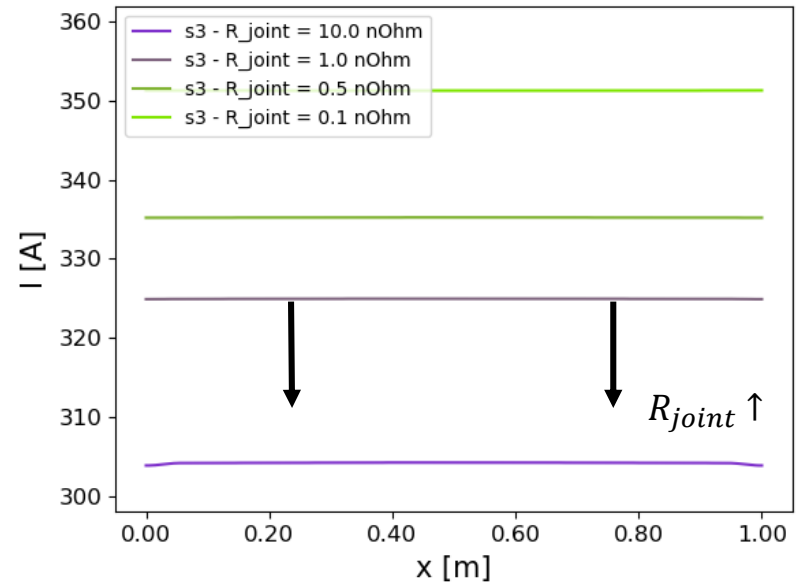
Parametric studies – Joint Resistance

We propose here a comparison of Currents for $R_{joint} = 0.1, 0.5, 1.0, 10.0 \text{ n}\Omega$

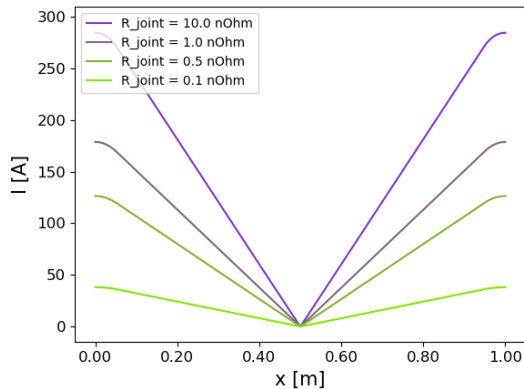
I(x) - Adjacent - R_{joint} Comparison



I(x) - Crossing - R_{joint} Comparison



I(x) - Broken - R_{joint} Comparison

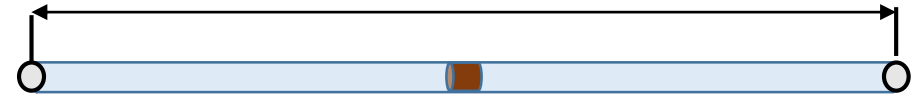


- As $R_{joint} \uparrow$, $I(x)$ is steeper in the adjacent strands; *less sharing to the crossing strands*, as well.
- **$R_{joint} \uparrow$ implies a general worse behaviour.**

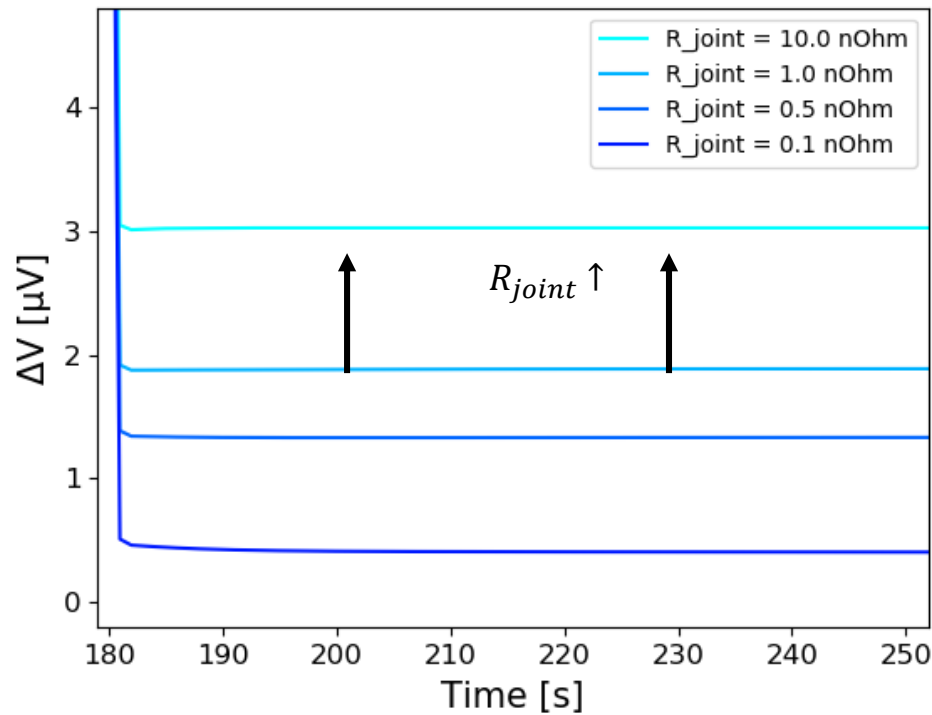
Parametric studies – Joint Resistance

We propose here a comparison of Voltages for $R_{joint} = 0.1, 0.5, 1.0, 10.0 \text{ n}\Omega$

$\Delta V (\Delta x = 90 \text{ cm})$



$\Delta V(t)$ - Broken

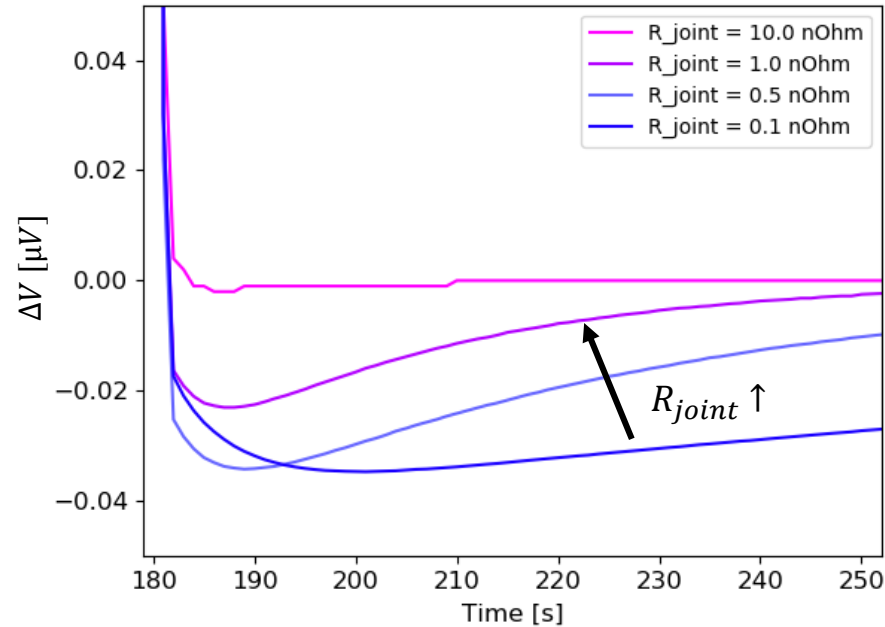


- As $R_{joint} \uparrow$, $I(x)$ profiles are steeper \rightarrow higher current transfer to adjacent strands \rightarrow higher ΔV s

Parametric studies – Joint Resistance

We propose here a comparison of Voltages for $R_{joint} = 0.1, 0.5, 1.0, 10.0 \text{ n}\Omega$

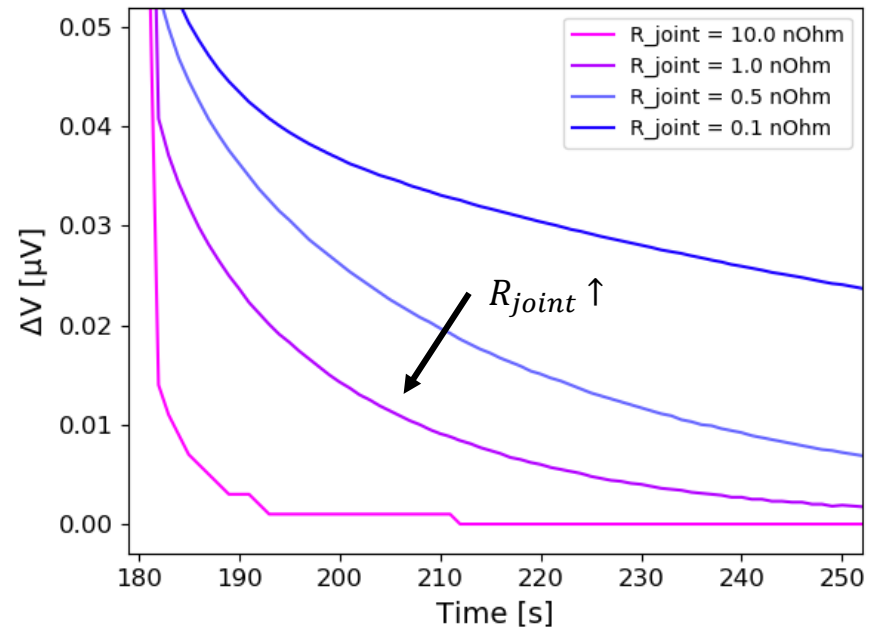
$\Delta V(t)$ - Adjacent



- As $R_{joint} \uparrow$, lesser inductive effect \rightarrow lesser decay on adjacent strands at ramp end \rightarrow lesser ΔV s

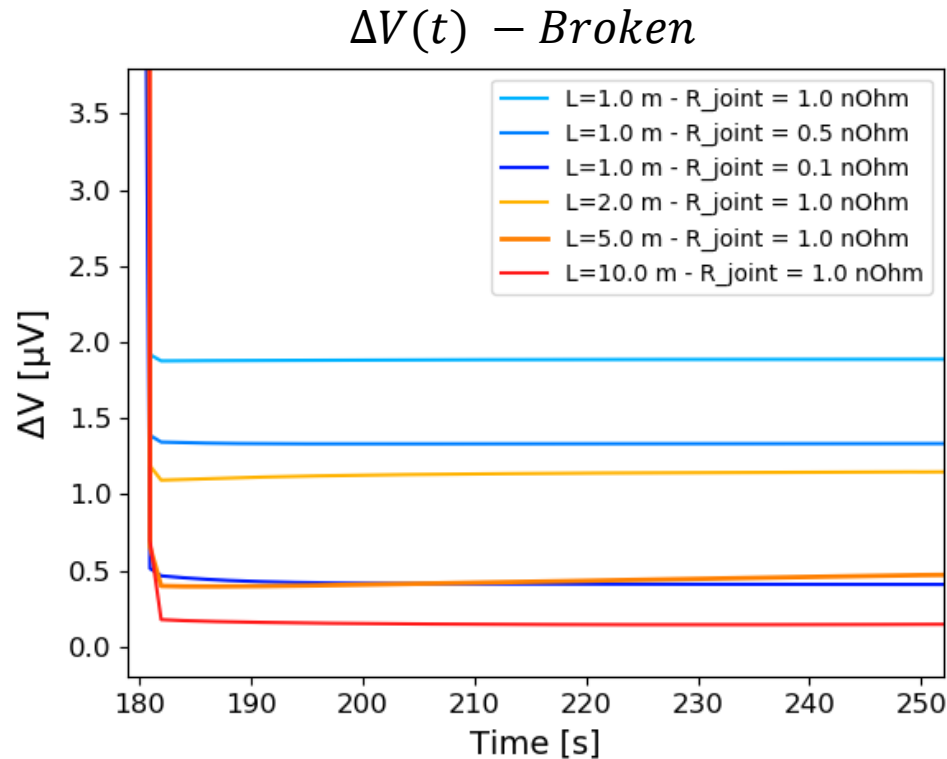
- As $R_{joint} \uparrow$, shorter τ s

$\Delta V(t)$ - Crossing



Parametric studies – System Length

We propose here a comparison of Voltages for a $R_{joint} = 1.0 \text{ n}\Omega$ & $L = 1.0, 2.0, 5.0, 10.0 \text{ m}$

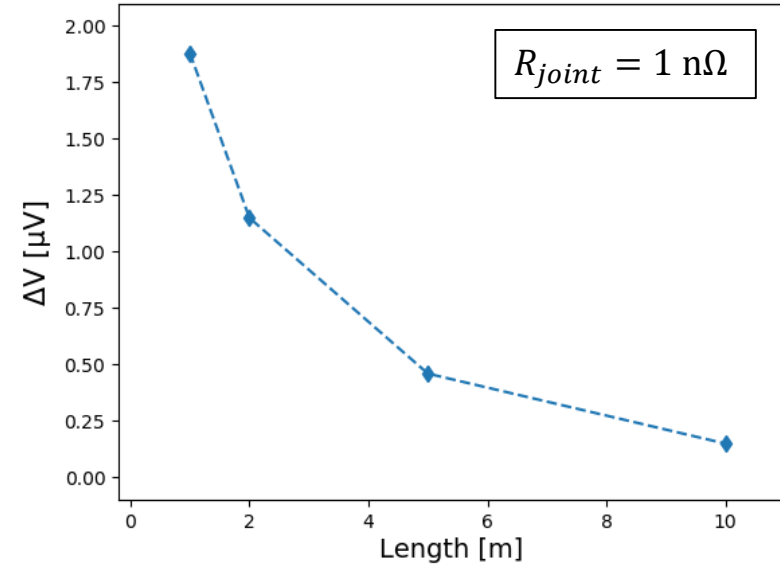


- At a given R_{joint} , increasing the domain length means lowering ΔV across the breakage
- One may think about an ‘equivalence’ between different combinations of L & R_{joint} . For example, here, $L=5.0 \text{ m}$ & $R_j=1 \text{ n}\Omega \Leftrightarrow L=1.0 \text{ m}$ & $R_j=0.1 \text{ n}\Omega$

Correlations

A few correlations may be noted:

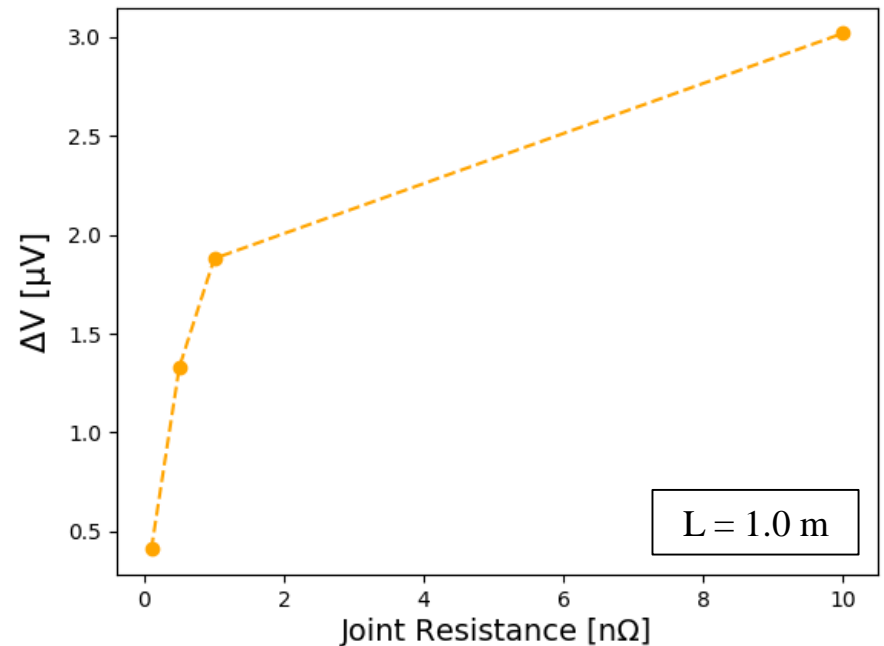
V drop as f(L)



- *Inverse proportion* between L and V drop across breakage

- “*Saturation*” of V drop above a given $R_{joint} \rightarrow$ uniform current distribution at the boundaries

V drop as f(R_{joint})



Conclusion

- A high joint resistance, R_{joint} , behaves as a strong voltage “pump”, forcing the current to flow into the broken strand. As a result, I profiles are steeper both in the broken and adjacent strands, putting system stability at a higher risk (since the adjacent strands take all the current from the broken strand).

→ *Low R joints are better*

- Viceversa, as R_{joint} decreases, boundaries go towards an *equi-V* condition: the broken strand is left with a lower current. The rest of the cable current is uniformly distributed among all non-broken strands (adjacent + crossing).
- Increasing the cable length L is equivalent to decreasing R_{joint} → a 10^3 long cable would converge towards an even better *equi-V* condition, with all crossing strands taking part in the current distribution process.

Next steps

- Parametric study on R_a vs R_c influence on the current distribution process (6-strand model)
- Go up to 40 strands and longer domains (10 \rightarrow 100 m)